



University of
Science & Technology

AES Sample Submission Form

(Please Print Information)
(Use separate form for samples of differing composition)

Name _____ Submission Date _____

E-mail _____ Advisor _____

Phone _____ Advisor's Signature _____

Department _____ MOCODE _____

Sample ID(s) _____

Composition

CIRCLE MAJOR, UNDERLINE MINOR or "POSSIBLE" elements

H																		He
Li	Be											B	C	N	O	F		Ne
Na	Mg											Al	Si	P	S	Cl		Ar
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br		Kr
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I		Xe
Cs	Ba	La	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At		Rn
Fr	Ra	Ac																
			Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu		
			Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lw		

Ion Sputtering Conditions

Approximate depth sample is to be sputtered to in Angstroms. _____

Approximate sputter rate to be used for PROFILING in Angstroms/minute. _____

Sputtering Interval between data pages. **Standard Run** or Specify Interval _____ min.

PROFILING can be stopped when the following condition is met. (Example: sample bulk composition is observed or (absence or presence) of particular element is observed, etc

Health Hazard: (Yes or No)

Environmental Hazard: (Yes or No)

If yes to either of the above, please explain

Sample Description(s)

Include information such as film thickness, surface details, and any other information, which might be significant to the analysis of the sample. If a particular area of the surface is to be analyzed provide a rough sketch of the sample indicating the areas of interest.

Sample Completion

Run Date: _____

Operator: _____

Batch/Position #(s):